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Atmospheric neutron testing of GaN power devices

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Wide bandgap power components are known for their resistance to both cumulative radiation damage and SEE, especially when compared to their silicon counterparts, and hence making them promising candidates for radiation tolerant accelerator systems. In this presentation, we show preliminary results of GaN power components recently tested with atmospheric neutrons at ChipIr (UK).

Presenter: SACRISTAN BARBERO, Mario (CERN-CIEMAT)

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